

September 20-22nd, 2016

G Hotel • Penang, Malaysia



Overview of IEMT-EMAP Conference

IEMT: International Electronics Manufacturing Technology

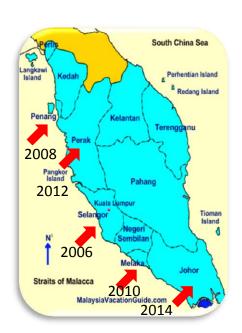
(2006, 2008, 2010, 2012, 2014, 2016 (In Progress))

EMAP: Electronics Materials and Packaging Conference

(2004, 2009, 2016 (In Progress))

IEMT is an international event organized by the IEEE CPMT Malaysia Chapter (rotation by cities) with co-sponsorship from CPMT society of IEEE, Santa Clara Valley Chapter.

- A major forum, providing opportunities to network and meet leading experts, in addition to exchange of up-to-date knowledge in the field.
- Since 1990's, IEMT has gained reputation as a premier electronic materials and manufacturing technology conference and well attended by experts all over the world.
- CPMT Malaysia took up the full conference ownership by Y2006.
- This year, we are organizing a joint conference between IEMT-EMAP2016, to be held at G-Hotel, Penang, Malaysia.



Organizing Team





























IEMT-EMAP 2016

The International Electronics Manufacturing Technology (IEMT) Conference is the premier IEEE event devoted to the manufacture of electronic, opto-electronic and MEMS/sensors devices and systems. IEMT is an established International conference of long standing organized by the Components Packaging and Manufacturing Technology (CPMT) Society of IEEE. The 37th International Electronics Manufacturing Technology (IEMT) - 18th Electronics Materials & Packaging (EMAP) Conference IEMT 2016 is being organized by the IEEE CPMT Malaysia Chapter with co-sponsorship from IEEE Santa Clara Valley Chapter.

- ☐ 8 Keynote Speakers
- ☐ 16 Invited Papers
- ☐ Oral Papers
- ☐ Poster Papers
- ☐ Exhibition Booths

2 SPECIAL SESSIONS

- ☐ CREST Session
- ☐ Akrometrix Session

Conference web link

http://ewh.ieee.org/r10/malaysia/cpmt/Home/iemt/2016/iemt2016.html

Download the Apps from Apple Apps Store and Google Apps Store



Secretariat

Hafiza Hamid

iemt-emap2016@crest.my

Collaborative Research in Engineering, Science & Technology sains@ usm

Block C, Ground Floor

No. 10 Persiaran Bukit Jambul

11900 Bayan Lepas Pulau Pinang, Malaysia Tel: +604 652 0088 Online Registration Link:

http://goo.gl/forms/ZuVlzgewfKG8ZHyW2





Short Courses

Klaus Mueller Infineon Technologies. Germany

Trends in Material Development – upcoming requirements concerning reliability A comprehensive overview about semiconductor technology trends and their impact on the development of packaging materials. The course will show the upcoming challenges of selecting materials with the focus on enhanced performance and greater functionality. The future materials must fulfill superior characteristics (e.g., conductivity, insulating behaviour, high temperature and voltage stability) under condition of proper cost management.



Ning-Cheng Lee Indium Corporation, USA

Achieving High Reliability for Lead-Free Solder Joints

This course covers detailed material considerations required for achieving high reliability for lead-free solder joints. Electro migration, corrosion, and tin whisker will also be discussed. The emphasis of this course is placed on the understanding of how the various factors contribute to the failure modes, and how to select proper solder alloys and surface finishes for achieving high reliability.



Charlie Lu Taiwan Printed Circuit Association (TPCA), Taiwan R.O.C

Chip-to-Package Interconnect Technology: Fundamentals and Future Trend

A review most of the conventional and newly developed chip-to-package interconnect technologies, including wire bonding, flip chip bonding, tape automatic bonding, via-interconnect, and surface activated bonding, etc. The characteristics, limitation, application, and future trend of each technology will be analysed by the nature of the process technique and material selection. This course is aimed to provide the forward-looking insight to the chip-to-package interconnect technology.



Christopher Breach ProMat Consultants, Singapore

Copper Ball Bonding Materials, Intermetallics & Reliability

Attendees of this short course will learn about copper wires and wire properties, the materials science that underlies the bonding process, intermetallics and the kinetics of intermetallic growth and failures related to wires and intermetallic degradation during reliability tests. This course is suitable for quality & reliability engineers and scientists, packaging development engineers and technicians and managers.



Seung Wook Yoon STATS ChipPAC, JCET Group, Singapore

Fan-out Wafer Level Packaging (FO-WLP) – Innovative and Novel Solutions of Advanced Packaging .

This course will give an overview and technical deep-drive of the FO-WLP technology. The market drivers, applications, cost benefits, industry readiness and challenges facing industry-wide adoption will be discussed. Typical FO-WLP configurations will be reviewed in terms of their construction, manufacturing processes and electrical / thermal / mechanical performance, together with package and board level reliability. Since the technology marks the convergence of fab, assembly, and test, the discussion will address questions on business model and technology challenges.





Eric WP Chan
Intel Corporation,
Malaysia

Development in Internet of Things (IoT) and Opportunities for "Packaging the IoT"



Anisotropic Conductive Films (ACFs) Interconnection Technology for Wearable





Rolf Aschenbrenner Fraunhofer IZM, German

Panel Level Embedding for Power and Sensor Applications Andy C Mackie
Indium Corporation,
USA

The Future of Power Device Packaging: Materials and Assembly Processes



Keynote Paper

Industry leading speakers are invited to deliver their sharing of the latest industry trends and opportunities



David Lacey Osram Opto Semiconductors, Malaysia

Material challenges for optoelectronic packages in lighting applications.

Ricky Lee HKUST, Hong Kong

Packaging and Integration Technologies for the Era of Internet of Things





Pierric Gueguen Yole Development, France

Technological challenges and market trends for power packaging

William T. Chen ASE Group, USA

Heterogeneous Integration Roadmap to the Brave New Interconnected World





Kishio Yokouchi

FUJITSU Interconnect Technologies, Lit.

Japan

Board Interconnect Technologies for Supercomputer "K" and the Next Generation



Hsiang-Chen Hsu

I-Shou University

Taiwan R.O.C

A Study on Package-on-Package with Through Molding Vias Using Laser Technology



Ming-Yi Tsai

Chang Gung University

Taiwan

Keep-out Zone and Mechanical Strength of Cu-TSV Chips Used in 3DIC



Seung Wook Yoon

STATS ChipPAC, JCET Group

Singapore

eWLB/FO-WLP : Novel Fan-Out Interconnect Solution

Invited Paper

Invited Distinguished Speakers' Papers

Rajkumar a/l Durairaj,

Universiti Tunku Abdul Rahman Malaysia

Investigation on the synthesis and conductivity mechanism of Graphene based Isotropic Conductive Adhesives Siow Kim Shyong

Universiti Kebangsaan Malaysia

Navigating the patent minefield of sintered silver (Ag) as a dieattach material in microelectronic packages. Mariatti Jaafar

Universiti Sains Malaysia

Application of Nanofillers in Polymer Composites for Electronic Packaging Mohd Nasir TAMIN,

Universiti Teknologi Malaysia

A Unified Framework for Solder Joint Reliability Assessment based on Damage Mechanics











Mohd Zulkifly Abdullah,

Universiti Sains Malaysia

Numerical prediction of resistor self-alignment during reflow soldering process



Ranjan Rajoo

Global Foundries Singapore

Solder Interconnection: Evolution & Revolution



A. S. M. A. Haseeb

University of Malaya

Nano meter Sized Metallic Additions to Lead-Free Interconnects: Effects on Microstructure and Properties



Shi-Wei Ricky Lee

Hong Kong University of Science and Technology

Precise Junction
Temperature Mapping
for Flip-chip Light
Emitting Diodes by
Infrared Thermography

Invited Paper

Invited Distinguish Speaker's Papers

Charlie Lu

TPCA

Taiwan

Review on the Newly Developed Fan-out Packages from Innovative Viewpoint Sung Yi

Portland State University

USA

Thin Packaging Technology

CP Hung

ASE Group

Taiwan R.O.C

New Era SiP Technologies with 3D Interconnection Lim Sze Pei

Indium Corporation

Malaysia

No Clean Material for Advanced Packaging Assembly



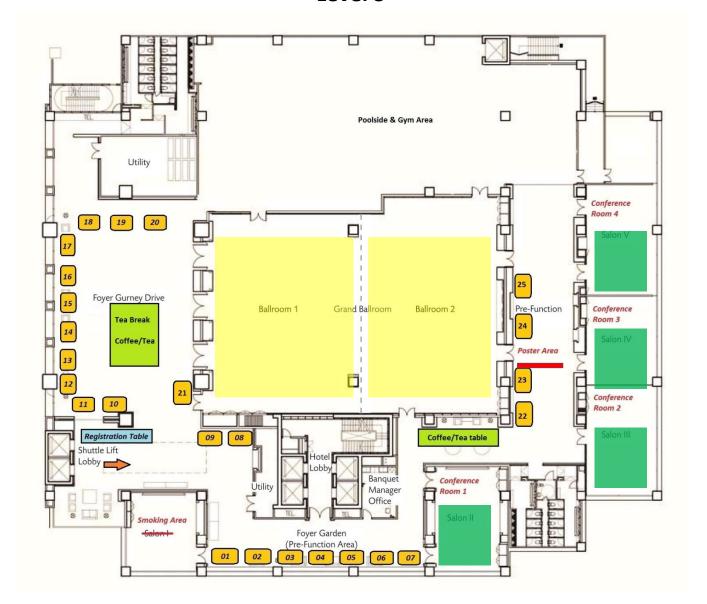






Conference Hotel Layout

G Hotel Penang Level 3



Functions	Location	Hotel Area
Registration		Reception Area
Opening, Closing, Keynote Sharing		Ballroom 1,2
Oral Presentation		Conference Room 1,2,3,4
Poster Presentation		Pre-Function
Exhibitor		Foyer, Pre-function





IEEE COMPONENT, PACKAGING AND MANUFACTURING TECHNOLOGY SOCIETY

	MITO	K SP	<u>ONSC</u>	DRSHIP	<u>& EX</u>	HIRLL	ION		IEMT-EMAP 2016
Organization	:								
Address:									
Telephone:						Facsi	mile :		
Person In Cha	arge :					Signa	ture :		
Email Addres	ss:								
				_	_				MAP 2016 that our company n(s) ticked below:
Туре	Cost	Tick your selection	Logo on banner	Logo on the conference bag	Logo on program book	Logo on sponsored item	Exhibition Booth	Details in Softcopy Proceeding ⁽²⁾	Remarks
Platinum Sponsors	RM15,000		Yes	Yes	Yes		Yes	Yes	3 seats for short course, conference & dinner
	RM12,000		Yes		Yes		Yes	Yes	3 seats for conference & dinner
Silver Sponsors	RM8,000		Yes		Yes			Yes	2 seats for conference & dinner
Bronze Sponsors	RM5,000				Yes			Yes	1 seat for conference & dinner
Sponsors						Yes ⁽¹⁾		Yes	eg. Thumbdrive, Pens etc
Conference Dinner :	RM6,000 RM1,500						Yes	Yes	~ 1.5x6 feet bench & 2 seats for lunch Sponsor may invite their guests to attend the dinner.
Sponsor 1 Table Seats 1) Sponsor's logo									Table with 10 seats
Exhibition will b	be for 2	days.			ınk Dr	aft / M o	oney O		Price quoted is in Malaysia Ringgit. Stal Order or Governement Loc M
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Signature:					Da	te:			
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Sponsorship &	ዿ Exhib	ition Er	nquiry:						
Email : lilykho	or@ca	rsem.	com						
Email : lilykho				.com					



37th International Electronics Manufacturing Technology/18th Electronics Materials & Packaging Conference (IEMT-EMAP 2016) G Hotel Penang Malaysia 20th = 22nd September 2016



G I	Hotel, Penang, N	Tafaysia. 20 FERENCE REGI) Manufacturing Technology Society
			SIKATIONT	JKWI	
A. Participant's Informatio	n (use additional she	et if needed).			
<u>Name</u>	Designation	<u> I</u>	Preferred Name	on Badge	IEEE Membership No.
)					
8. Contact Information					
Irganization:	D	ant :	Tal·		Fax :
Iailing Address:					
City/State:	Zip :	Country	/:	Email :	
	REGIS	STRATION	FEE DETA	AILS	
ART I : CONFERENCE RE					ordingly).
					EFORE 15 TH AUGUST 2016)
CONFERENCE ON 21°	CONFERE			OURSE FEE	CONFERENCE + SHORT COURSE
SPEAKERS	F 3	M650	F 3	RM600	RM1200
			F 3		F 3
DIEEE MEMBER NON IEEE MEMBER	F 3	M750 M850	F 7	RM600 RM700	RM1250
FULL TIME STUDENTS		M600	F 3		5.3
ATE FEE CHARGE – A late fee cha				RM500 fter 15 th August 2016	[] RM1000
Note: 1 Ringgit (MYR) is approximate				TOTAL AMOUNT	,
ART II : SHORT COURSE	SHORT CO	URSE ON 20 ST SEPTI	EMBER 2016 (1 FU	JLL DAY)	B* y /
MORNING SHORT	COURSE (8:15 – 12:15 PM	M)	Al	TERNOON SHORT	COURSE (1:30 – 5:30 PM)
[] Short Course I (Full Day)					
Instructor: Charlie Lu	ige Interconnect Techn		als and Future T	rend	
Taiwan Printed [] Short Course II (Full Day)	Circuit Association (TP	CA), TAIWAN			
	Level Packaging (FO-	WLP) – Innovative	and Novel Solu	tions of Advanced	Packaging
Instructor: Dr. Yoon Seun		,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	110 101 2014		· · · · · · · · · · · · · · · · · · ·
	C-JCET, SINGAPORE				
[] Short Course III (Full Day Fopic: Copper Ball B) onding Materials, Inter	matallia & Daliahi	lite.		
Instructor: Or. Christopher		i inetaine & Kenabi	iity		
ProMat Consul	tants, SINGAPORE				
Short Course IV-A (Half D	• *		[] Short Cou Topic :	rse IV-B (Half Da	
	terial Development – Uj Concerning Reliability	elopment – Upcoming		Achieving High Joints	Reliability for Lead-Free Solder
Applications	Concerning Renability	-	Dr. Ning Cheng	Lee	
Instructor: Dr. Klaus Muel	Klaus Mueller				
Infineon Techn			Instructor:	Indium Corpora	tion, USA
	ologies, GERMANY		Instructor:		tion, USA
	ologies, GERMANY	DETAILS (IN M		Indium Corpora	tion, USA
egistration is limited so please regeviously faxed. All payment for t	PAYMENT gister early. To register,	fill out registration	ALAYSIAN R	Indium Corpora INGGIT) ong with check or	bank draft payment. Please do not ma
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Mail or fax registration form to:

IEMT-EMAP 2016 Secretariat, (Attention: Hafiza Hamid)

CREST, Sains@USM, Block C, Ground Floor, No. 10, Persiaran Bukit Jambul,

11900 Bayan Lepas, Penang, MALAYSIA

Tel: +6-04-652-0088 Fax: +6-04-652-0099

Email: <u>iemt-emap2016@crest.my</u> Conference website: http://ewh.ieee.org/r10/malaysia/cpmt/Home/iemt/2016/iemt2016.html





Experiences ... Stylishly

G HOTEL GURNEY

168A Persiaran Gurney, 10250 Penang, Malaysia T.+604 238 0000 F.+604 238 0088 Email: g4u@ghotel.com.my www.ghote.com.my

Accommodation And Conference Venue

Ultra chic with stunning contemporary interiors, G Hotel Gurney houses 312 rooms and is located in a prominent location next to upscale shopping malls and renowned hawker eateries nearby. The hotel is the perfect point of departure for discovering Penang wonders like tourist attractions, UNESCO world heritage sites and beaches. G Hotel Gurney aims to deliver a refreshing guest experience through its modern facilities & impeccable service standards.

FACILITIES

SURF @ G | GYMNASIUM | INFINITY POOL | DANAI SPA | BAPTAIN HAIR SALON

RESTAURANTS AND BARS

TASTE CAFE Serving an array of International buffet spread and local savouries whilst offering guest a relaxing ambience with an indoor & outdoor alfresco area.

The hotel offers several bars including G lounge, Tree Bar and G Pool Bar

ROOMS

Featuring beautiful views of the coast, the air-conditioned rooms at G Hotel are decorated in soothing neutral colours. Each is equipped with a satellite TV, free minibar and tea/coffee making facilities.

PROMINENT LOCATION
ON THE BUSTLING
PERSIARAN GURNEY

IEMT - EMAP 2016 PROGRAM OVERVIEW: 20th - 22nd SEPT 2016

	SHORT COURSES : 20th SEPTEMBER 2016, TUESDAY						
0800 - 0830	Registration at Secretariat						
	ROOM: SALON II	ROOM: SALON III	ROOM: SALON IV	ROOM: SALON V			
	FULL DAY	FULL DAY	FULL DAY	MORNING SESSION			
0830 - 1730 (Inclusive of lunch and cofee breaks)	Chip-to-Package Interconnect Technology: Fundamentals and Future Trend	Fanout Wafer Level Packaging (FO- WLP) – Innovative and Novel Solutions of Advanced Packaging	Copper Ball Bonding Materials, Intermetallic & Reliability	Trends in Material Development – Upcoming Requirements Concerning Reliability and Applications Klaus Mueller Infineon Technologies, GERMANY AFTERNOON SESSION			
	Charlie Lu Taiwan Printed Circuit Association (TPCA), TAIWAN	Seung Wook Yoon STATSChipPAC-JCET, SINGAPORE	Christopher Breach ProMat Consultants, SINGAPORE	Achieving High Reliability for Lead-Free Solder Joints Ning Cheng Lee Indium Corporation, USA			

EXHIBITION - 21st SEPTEMBER 2016, WEDNESDAY

	CONFERENCE	SESSIONS (DAY 1): 21st SE	PTEMBER 2016, WEDNESDA	YY				
0730 - 1730	Registration at Secretariat							
	Opening Ceremony & Keynote Addresses at Grand Ballroom							
0730 - 0815	Guests and Participants Arrival Into Grand Ballroom.							
	Welcome Speech by Tze Yang Hin, IEMT-EMAP 2016 General Chair							
0830 - 0915			Chairman, IEEE-CPMT Malaysia Chapter					
	Confere		EEE-CPMT Society, Represented by Willian	m Chen				
	Marin da	Heterogeneous Integration : Roadmap t		46 - 1- TI				
0915 - 1000	Keynote	· · · · · · · · · · · · · · · · · · ·	ngs (IoT) and Opportunities for "Packaging	the IO I "				
	Eric Chan, Intel Corporation, MALAYSIA Keynote Address II: Panel Level Embedding For Power and Sensor Applications							
1000 - 1045	Rolf Aschenbrenner, Fraunhofer Institute for Reliability and Microintegration Berlin (IZM), GERMANY							
1045 - 1110		Coffee Breaks/	Poster Session					
	ROOM : SALON II	ROOM : SALON III	ROOM: SALON IV	ROOM: SALON V				
	SESSION A1	SESSION B1	SESSION C1	SESSION D1				
1110 - 1250	ADVANCED PACKAGING I	PROCESS	CREST SESSION	AKROMETRIX SESSION				
	ADVANCED FACKAGING I	PROCESS	CREST SESSION	ARROWETRIA SESSION				
1250 - 1400		Buffet	Lunch					
1400 - 1445	Keynote Address III:	Anisotropic Conductive Films (ACFs) Inter	connection Technology for Wearable Elect	ronics Applications				
1400 1440		KW Paik, KA	- 1 - 1					
1445 - 1530	Keyn		e Packaging: Materials and Assembly Proc	esses				
1530 - 1600	Andy MacKie, Indium Corporation, USA Coffee Break/Poster Session							
1000 1000	ROOM : SALON II	ROOM : SALON III	ROOM : SALON IV	ROOM: SALON V				
	SESSION A2	SESSION B2	SESSION C2	SESSION D2				
1600 - 1720								
1000 1720	ADVANCED PACKAGING II	SOLDER MATERIALS I	THERMO-MECHANICAL	DESIGN				
		DINNER/CUI	FURAL SHOW					
1900 - 2300		DINNER AND CULTURAL PERFORI	WANCE BY MALAYSIAN TOURISM					
	(Dinner/Cultural Show in the Grand Ballroom)							

EXHIBITION - 22nd SEPTEMBER 2016, THURSDAY Tabletop Display Outside of Conference Room

	CONFERENCI	E SESSIONS (DAY 2) : 22nd S	SEPTEMBER 2016, THURSDA	Υ					
0730 - 0830	Registration at Secretariat								
0830 - 0915	Keynote Address V: Material Challenges for Optoelectronic Packages in Lighting Applications								
0630 - 0913		David Lacey, Osram Opto S	Semiconductors, MALAYSIA						
0915 - 1000	К	Keynote Address VI: Technological Challenges and Market Trends For Power Packaging							
		<u> </u>	Developpment, FRANCE						
1000 - 1030	Door On our		Poster Session						
	ROOM: SALON II	ROOM : SALON III	ROOM: SALON IV	ROOM: SALON V					
1030 - 1230	SESSION A3 SUBSTRATE TECHNOLOGY	SESSION B3 WIREBOND	SESSION C3 RELIABILITY I	SESSION D3 MATERIALS					
1230 - 1400		Buffet	Lunch						
	ROOM: SALON II	ROOM: SALON III	ROOM: SALON IV	ROOM: SALON V					
1400 - 1600	SESSION A4 SOLDER MATERIALS II	SESSION B4 MATERIALS & PROCESSING	SESSION C4 RELIABILITY II	SESSION D4 TEST & METHODOLOGY					
1600 - 1620		Coffee Break/I	Poster Session						
1620 - 1705	Conference Closing	g Address Keynote Address VII: Packaging Ricky Lee, Hong Kong University of S		f Internet of Things					
		AWARD PRESENTATION AND CE	NFERENCE CLOSING CEREMONY						